Am26L02/96L02

Low Power Dual Retriggerable Resettable Monostable Multivibrators

Distinctive Characteristics:

- One-fourth the power of the equivalent Am2602/9602 dual single shots.
- 50 ns typical propagation delay.
- · Fan-out of 3 with standard TTL circuits.
- Guaranteed pulse width variation versus temperature.
- 100% reliability assurance testing in compliance with MIL STD 883
- Electrically tested and optically inspected die for the assemblers of hybrid products
- Mixing privileges for obtaining price discounts.
 Refer to price list
- Available in highly reliable molded epoxy, hermetic dual-in-line or Hermetic flat package.

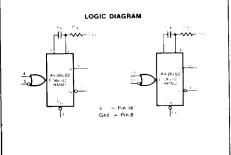
FUNCTIONAL DESCRIPTION

The Am 26L02 and 96L02 are low-power dual DC-level sensitive resettable retriggerable monostable multivibrators which provide an output pulse whose duration and accuracy depend on external timing components.

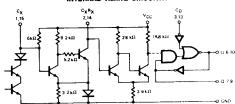
Provision is made for triggering on the rising or falling edge of an input signal. All inputs are DC coupled making triggering independent of input rise and fall times. Each time the output from the OR trigger gate goes from a FALSE (LOW) to TRUE (HIGH) condition triggering occurs independent of the state of the monostable.

The direct clear facility allows a tuning cycle to be terminated at any time during the cycle. A LOW signal on the $\overline{\mathbf{C}}_D$ input resets the monostable independent of other conditions.

The Am26L02 has a guaranteed pulse width variation versus temperature of only 1% over the temperature range 0°C to $+75^{\circ}\text{C}$



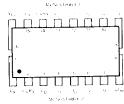
INTERNAL TIMING CIRCUITRY



ORDERING INFORMATION

	OKDEHING	IMPORMATION	
Part Number	Package Type	Temperature Nange	Order Number
Am26L02	Molded DIP	0°C to +75°C	Am26L0259A
Am26L02	Hermetic DIP	0°G to +75°C	Am26L0259E
Am26L02	Hermetic DIP	-65°C ta +125°C	Am26L0251E
Am26L02	Hermetic Flat Pak.	-65°C to +125°C	Am26L0251N
Am26L02	Dice 😘	Note	Am26L02XXD
Am96L02	Moided DIP	∪ 0°C to +75°C	U6M96L0259X
Am96L02	Hermetic DIR	0°C to +75°C	U7B96L0259X
Am96L02	Harmetic Diff	-55°C to +125°C	U7B96L0251X
Am96L02	Sermetic Flat Pak	-55°C to +125°C	U4L96L0251X
Am96L02	Dice	Note	UXX96L02XXE
Note: The di-	ce supplied will contain 55°C to +125°C temper	n units which meet bo sture range.	oth 0°C to +75°

CONNECTION DIAGRAM Top View



MAXIMUM	VGS (Above which the useful life may be impaired)		
Storage Temps.	18	-65°C to +150	
Temperature (Ambient) Under Bias			
		-55°C to +125	
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous		-0.5 V to 4	
DC Voltage Applied to Outputs for High Output State		-0.5 V to +V _{CC} m	
DC Input Voltage		~0.5 V to +5.5	
Output Current Into Outputs When Output is LOW			
DC Input Current			
		-30 m h t- 15	

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

rameters Description		Test Conditions (Note 1) Min.		Typ. (Note 1)	Max.	Units	
V _{OH}	Output HIGH Voltage	$V_{CC} = MIN., I_{OH} = -0.36 \text{ mA}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	2.4	3.6		Volta	
Va	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 4.92 mA V _{IN} = V _{IH} or V _{IL}		0.15	0.3	Volt	
V _{iH}	Input HIGH Level	Guaranteed input logical HiGH voltage for all inputs	2.0			Volt	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.7	Volt	
i _{(L} (Note 2)	93L Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.3 V		-0.25	-0.4	mA	
I _H	93L Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.4 V		2.0	20	μΑ	
(Note 2)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0	mA	
Isc	Output Short Circuit Current	V _{CC} = MAX., V _{OUT} = 1.0 V	-2.0				
lcc	Power Supply Current	V _{CC} = MAX.	-2.0	10	-13 16	mA mA	

Switching Characteristics (TA = 25°C)

Parameters			Test Conditions	Min	.		
t _{pd+}	Turn Off Delay Negative Trigger Input	Am26/96L0251X	- I CONTRIDITE	MINT	Тур 55	Max 75	Unit
	to True Output	Am26/96L0259X			55	80	ns
t _{pd} _	Turn On Delay Negative Trigger Input to False Output		$V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}$ $R_X = 20 \text{ k}\Omega, C_X = 0 \text{ pF}$		42	62	ns
t _{pw} (min)	Minimum True Output Pulse Width	 			440		
7	Pulse Width at True Output		$V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}$ $R_X = 39 \text{ k}\Omega, C_X = 1000 \text{ pF}$	12.4	110 13.8	15.2	PLS PLS
R _X Timing Resistor (Note	Timing Resistor (Note 2)	Am26/96L0251X		20		200	 - -
• (5)	Date of the second seco	Am28/96L0259X		16		220	KO
$\mathbf{t}_{pd-}(C_0)$	Delay from C _D to Q output LOW				27	40	ns
ΔT Maxim over o		Am96L0259X		0	0.3	1.6	-
	Maximum Change in Pulse Width True Output	Am96L0251X	$V_{CC} = 5.0 \text{ V}, C_1 = 15 \text{ pF}$ $R_1 = 39 \text{ k}\Omega, C_2 = 1000 \text{ pF}$	0	1.3		i
	over operating temperature range	Am26L0259X Am26L0251X		<u> </u>	0.3	1.0	%
latar 1 7				0	1.0	4.0	

: 1. Tests are conducted with a 38 kD resistor placed between Pin 2 (14) and V_{CC} unless otherwise noted. 2. Maximum permissible R_χ when used below 0°C is 100 kD.

Notes: 1: Typical limits are at $V_{CC} = 5.0 \text{ V}$. 25°C emblent and maximum loading.

2: Actual input currents are obtained by multiplying unit load current by the SSL input load factor. (See loading rules)

OPERATION RULES

- An external resistor R_x and an external capacitor C_x are required as shown in the togic diagram. The values of R_x may vary from 20 kH to 200 kH for 0°C to +75°C operation and 20 kH to 100 kD for -55°C to +125°C operation. C_x may vary from 0 to any value necessary and obtainable.
- 2. If a fixed value of R_x is used, the following values are recommended: R_x = 120 kU for 0°C to +75°C operation, R_x = 38 kU for -55°C to +125°C operation.
- 3. The output pulse width T is defined as follows:
- $T = 0.33 \, R_x C_x \left(1 + \frac{3.0}{R_x}\right) \qquad \text{(For } C_x \text{ greater than 101 pF)} \qquad \text{Where: } R_x \text{ is in kil), } C_x \text{ is in pF. T is in ns} \qquad \text{For } C_x = 10 \cdot \text{pF see Fig. 3}$
- 4. If electrolytic type capacitors are to be used, the following two arrangements are recommended





This circuit also allows larger value of R to be used for longer output pulse width.

R . R, (0.7) (h,,Q) R. (min) - R. - R. (max) Q Any NPN sition device with sufficient h,, at low currents. such as 2N2511

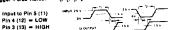
Both circuits prevent reverse voltage across C_{χ^*} . The pulse width T for the circuits is defined as follows

$$T\approx 0.30~RC_{\chi}~\{1+\frac{3.0}{R}]$$
 Where: R is in $k\Omega,~C_{\chi}$ is in pF, $~T$ is in ns.

To obtain variable pulse width, by remote trimming, the following circuit is recommended



- Under any operating condition, C_x and R_x (min) must be kept as close to the circuit as possible to minimize stray capacitance and reduce noise pickup
- t, t, t, t, > 60 ms 7. Input Trigger Pulse Rules.



Input to Pin 4 (12) Pin 5 (11) = HIGH Pin 3 (13) = HIGH



8. The retriggerable pulse width is calculated as shown below:

$$t_{\nu} = t_{pm} + t_{pol+} = 0.33 R_{x}C_{x} (1 + \frac{3.0}{R_{x}}) + t_{pol+}$$

The retrigger pulse width is equal to the pulse width $t_{\mu\nu}$ plus a delay time For pulse widths greater than 500 ns. $t_{\rm c}$ can be approximated as $t_{\rm pul}$

NOTE: Retriggering will not occur if the retrigger pulse comes within 0.33 $R_x C_x (\frac{3.0}{R_x})$ in after the initial trigger pulse

9. Reset Operation - The Am26L02/96L02 have an active LOW reset facility. By applying a low to the reset input, any timing cycle can be terminated or any new cycle inhibited until the low reset input is removed. Trigger inputs will not produce spikes in the output when the reset is held tow

DEFINITION OF TERMS

SUBSCRIPT TERMS:

- M HIGH, applying to a HIGH logic level or when used with ${
 m V}_{CC}$ to indicate high $V_{\rm CC}$ value.
- I Input.
- L LOW, applying to LOW logic level or when used with $V_{\rm CC}$ to indicate low V_{CC} value.
- Output.

OPERATIONAL TERMS:

- II. Forward input load current.
- I_{OH} Output HIGH current, forced out of output in V_{OH} test.
- Io. Output LOW current, forced into the output in Vol. test.
- I_{IN} Reverse input load current.
- Negative Current Current flowing out of the device.
- Positive Current Current flowing into the device.
- Y_{IH} Minimum logic HIGH input voltage. Refer to figure 2.
- YiL Maximum togic LOW input voltage. Refer to figure 2.
- YOH Minimum logic HIGH output voltage with output HIGH current I_{OH} flowing out of output.
- You Maximum logic LOW output voltage with output LOW current l_{OL} into output.

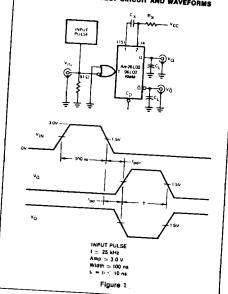
FUNCTIONAL TERMS:

- $\overline{m{c}}_{m{0}}$. The asynchronous direct clear input. A LOW on this input resets the monostable independent of other conditions.
- Fan-Out The logic HIGH or LOW output drive capability in terms
- of Input Unit Loads. The active LOW input of the monostables. With input I, LOW a
- HIGH to LOW transition on T will cause triggering. I, The active HIGH input of the monostables. With \overline{I}_a HIGH a LOW
- to HIGH transition on I, will cause triggering. input Unit Load One T1L gate input load.
- The TRUE output of the monostables.
- The FALSE output of the monostables.
- Triggering The switching of the monostable from the stable state to the unstable state and start of the timing cycle.

SWITCHING TERMS:

- The propagation delay from a HIGH to LOW transition on \overline{I}_0 to the true (Q) output LOW to HIGH transition.
- $oldsymbol{1}_{\mathrm{od}}$. The propagation delay from a HIGH to LOW transition on $\overline{oldsymbol{1}}_{\mathrm{o}}$ to the false (Q) output HIGH to LOW transition.
- $t_{o_{x}}$ (min) The minimum true (Q) output pulse width with $R_{\chi}=20~k\Omega$, $\dot{C}_x = 0 \text{ pF}.$
- The pulse width obtained with $R_\chi=39~k\Omega,~C_\chi=1000~pF.$
- ΔT The maximum percentage change in pulse width of the true (Q) output over the temperature range from the pulse width at 25°C.

SWITCHIN. - IME TEST CIRCUIT AND WAVEFORMS



TRUTH TABLE

Am26L02/96L02 For Each Monostable

, io		, Ĉ	Operation
H→L	L	н	Trigger
H	L→H	н	Trigger
^	^	L	Poset

H = HIGH Voltage Level

L = LOW Voltage Level

X = Don't Care

H→L = HIGH to LOW Voltage Level transition L→H = LOW to HIGH Voltage Level transition

INPUT/OUTPUT INTERFACE CONDITIONS

Voltage Interface Conditions — LOW & HIGH

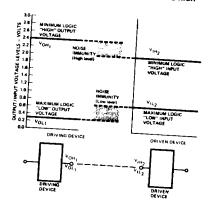
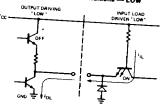
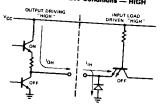


Figure 2

Current Interface Conditions — LOW



Current Interface Conditions - HIGH



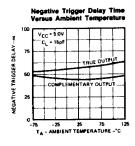
Am26L02/96L02 LOADING RULES

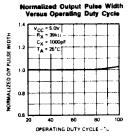
93L00 SERIES UNIT LOADS 9300 SERIES UNIT LOADS

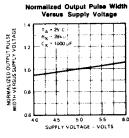
			Fanout		Input Unit Load		Fanout	
Input/Output	Pin No.'s	input Unit Load	Output HIGH	Output LOW	Input HIGH	Input LOW	Output HIGH	Output LOW
Monostable 1 C _x	1	I –			I -		-	
C _x A	x 2	-	_		-	_	-	
¯C _D	3	1	_		0.5	0.25	_	<u> </u>
I,	4	1	_	_	0.5	0.25	_	_
Ī,	5	1			0.5	0.25	_	_
a	6	_	12	12			6	3
Q	7		12	12			6	3
GNE	8	_	_		<u> </u>	_		
Monostable 2 Q	9		12	12	_	· · · · · · ·	6	3
Q	10		12	12			6	3
ī,	11	1		_	0.5	0.25	_	_
I, C _D	12	1			0.5	0.25	_	_
	13	1	_	_	0.5	0.25		_
	x 14	_	_		T	· ·		-
C _x	15	_	_		T	-	_	_
V _{cc}	16	_			_	· · · - ·	_	

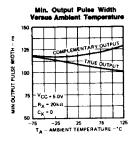
Table I

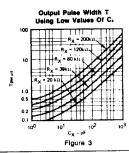
Typical Pulse Characteristics

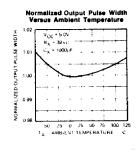


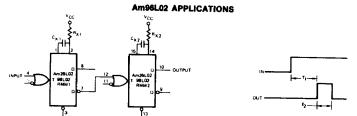








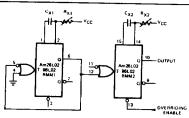




Delayed Pulse Generation

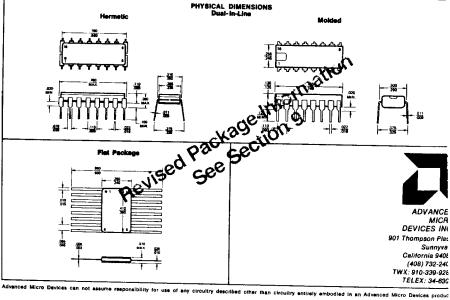
The first monostable determines the time T, before the initiation of the output pulse. The second monostable determines T2, the output pulse width.

Figure 5



The output frequency produced with the above configuration is determined by $\mathbf{C}_{\mathbf{x}_1}$ and $\mathbf{R}_{\mathbf{x}_{11}}$ while the pulse width is determined by C_{x_2} and R_{x_2} . Monostable 1 forms an astable multivibrator with an output pulse width of approximately 110 ns, while monostable 2 extends the pulse width to the required value.

Figure 6



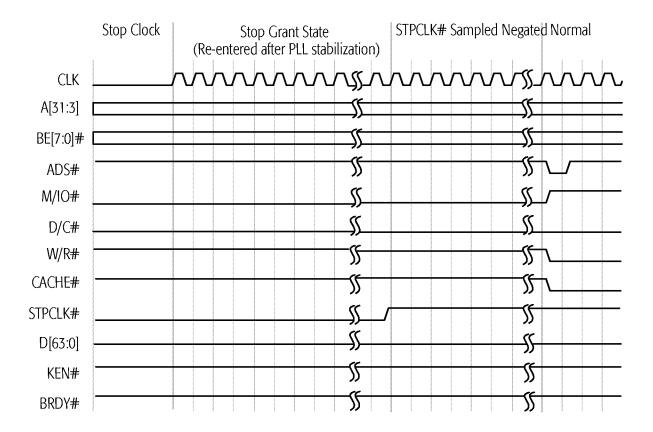


Figure 75. Stop Grant and Stop Clock Modes, Part 2

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INIT-Initiated Transition from Protected Mode to Real Mode

INIT is typically asserted in response to a BIOS interrupt that writes to an I/O port. This interrupt is often in response to a Ctrl-Alt-Del keyboard input. The BIOS writes to a port (similar to port 64h in the keyboard controller) that asserts INIT. INIT is also used to support 80286 software that must return to Real mode after accessing extended memory in Protected mode.

The assertion of INIT causes the processor to empty its pipelines, initialize most of its internal state, and branch to address FFFF_FFF0h—the same instruction execution starting point used after RESET. Unlike RESET, the processor preserves the contents of its caches, the floating-point state, the MMX state, Model-Specific Registers (MSRs), the CD and NW bits of the CR0 register, the time stamp counter, and other specific internal resources.

Figure 76 shows an example in which the operating system writes to an I/O port, causing the system logic to assert INIT. The sampling of INIT asserted starts an extended microcode sequence that terminates with a code fetch from FFFF_FFFOh, the reset location. INIT is sampled on every clock edge but is not recognized until the next instruction boundary. During an I/O write cycle, it must be sampled asserted a minimum of three clock edges before BRDY# is sampled asserted if it is to be recognized on the boundary between the I/O write instruction and the following instruction. If INIT is asserted synchronously, it can be asserted for a minimum of one clock. If it is asserted asynchronously, it must have been negated for a minimum of two clocks, followed by an assertion of a minimum of two clocks.

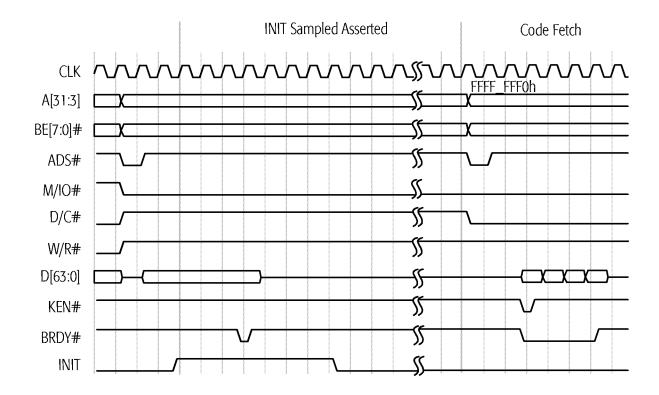


Figure 76. INIT-Initiated Transition from Protected Mode to Real Mode

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6 Power-on Configuration and Initialization

On power-on the system logic must reset the AMD-K6-2 processor by asserting the RESET signal. When the processor samples RESET asserted, it immediately flushes and initializes all internal resources and its internal state, including its pipelines and caches, the floating-point state, the MMX and 3DNow! states, and all registers. Then the processor jumps to address FFFF FFF0h to start instruction execution.

6.1 Signals Sampled During the Falling Transition of RESET

FLUSH#

FLUSH# is sampled on the falling transition of RESET to determine if the processor begins normal instruction execution or enters Tri-State Test mode. If FLUSH# is High during the falling transition of RESET, the processor unconditionally runs its Built-In Self Test (BIST), performs the normal reset functions, then jumps to address FFFF_FFF0h to start instruction execution. (See "Built-In Self-Test (BIST)" on page 217 for more details.) If FLUSH# is Low during the falling transition of RESET, the processor enters Tri-State Test mode. (See "Tri-State Test Mode" on page 218 and "FLUSH# (Cache Flush)" on page 103 for more details.)

BF[2:0]

The internal operating frequency of the processor is determined by the state of the bus frequency signals BF[2:0] when they are sampled during the falling transition of RESET. The frequency of the CLK input signal is multiplied internally by a ratio defined by BF[2:0]. (See "BF[2:0] (Bus Frequency)" on page 92 for the processor-clock to bus-clock ratios.)

BRDYC#

BRDYC# is sampled on the falling transition of RESET to configure the drive strength of A[20:3], ADS#, HITM#, and W/R#. If BRDYC# is Low during the fall of RESET, these outputs are configured using higher drive strengths than the standard strength. If BRDYC# is High during the fall of RESET, the standard strength is selected. (See "BRDYC# (Burst Ready Copy)" on page 95 for more details.)

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6.2 RESET Requirements

During the initial power-on reset of the processor, RESET must remain asserted for a minimum of 1.0 ms after CLK and V_{CC} reach specification. (See "CLK Switching Characteristics" on page 255 for clock specifications. See "Electrical Data" on page 247 for V_{CC} specifications.)

During a warm reset while CLK and $V_{\rm CC}$ are within specification, RESET must remain asserted for a minimum of 15 clocks prior to its negation.

6.3 State of Processor After RESET

Output Signals

Table 31 shows the state of all processor outputs and bidirectional signals immediately after RESET is sampled asserted.

Table 31. Output Signal State After RESET

Signal	State	Signal	State
A[31:3], AP	Floating	LOCK#	High
ADS#, ADSC#	High	M/IO#	Low
APCHK#	High	PCD	Low
BE[7:0]#	Floating	PCHK#	High
BREQ	Low	PWT	Low
CACHE#	High	SCYC	Low
D/C#	Low	SMIACT#	High
D[63:0], DP[7:0]	Floating	TDO	Floating
FERR#	High	VCC2DET	Low
HIT#	High	VCC2H/L#	Low
HITM#	High	W/R#	Low
HLDA	Low	_	_

Registers

Table 32 on page 175 shows the state of all architecture registers and Model-Specific Registers (MSRs) after the processor has completed its initialization due to the recognition of the assertion of RESET.